L Number	Hits	Search Text	DB	Time stamp
1	100	digital adj sampling adj oscilloscope	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 10:25
2	11	(digital adj sampling adj oscilloscope) with test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 10:21
3	5	(digital adj sampling adj oscilloscope) with probe	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 10:24
4	5	(digital adj sampling adj oscilloscope) with tester	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 10:25
5	0	(digital adj sampling adj oscilloscope) with dut	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 10:25
6	639	impedance and tester and probe and substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:10
7	9176	324/754-765.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 10:27
8	196	(impedance and tester and probe and substrate) and 324/754-765.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:08
9	1055	324/765.cor.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:08
10	29	(impedance and tester and probe and substrate) and 324/765.cor.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:09
11	1029	324/754.cor.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:10
12	275	324/761.cor.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:10
13	221	324/763.cor.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:10
14	72	(impedance and tester and probe and substrate) and 324/754.cor.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/10 11:10